

QUAD development

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Nikhef/Bonn LepCol meeting November 20, 2017

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Electrical QUAD 2 assembled and installed

- 2 Class A chips, wrinkled grid
- HV grid contact to very narrow dyke very problematic
 - Delaminated at the class A chips
 - Contact by Traduct silver glue
 - Passivated by Araldite
 - Mechanical strength
 - Insulation
- Mounting guard
 - Positioning with XYZ stage
 - 2^{nd} screw (M1.2) did not fit
 - Error in hole to hole distance?
 - At both ends secured with minor amount of Araldite
 - Problem expected to be solved for new generation wirebond boards and guards
- Jean Paul is making a new guard from coppered glass fibre epoxy





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Assembly in test box







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Assembly in test box cntd







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First HV tests

- Done with ISEG HV supply and HV probe (1 GΩ impedance)
- Grids connected by HV board
 - 100 M Ω and 50 M Ω
- Test in air
- All grids had correct HV
- Initially high current (600 nA @ 50V
 - Decreasing to 170 nA @ 200 V



- Under gas trip at 200 V
 - After 10 h at 100 V also trip
- After weekend ramping up to 200 V
 - 1st trip after 1 min
 - ^{2nd} trip after 10 min
 - **3**rd trip after 40 min

QUAD 2 tested in gas

- Flushing with T2K
 - => 2.3% O₂ at 3 ml/min on long term (box has 700 ml content)
 - => 1.1% O₂ by replacing the rubber of the flex feedthrough
- Initially HV problems
 - **Test up to 200 \text{ V} => \text{trip}**
 - Long term curing at 100 V => trip after 8 h
 - Next day ramp up to 200 V
 - Trip after 1 min
 - Trip after 10 min
 - Trip after 40 min
 - No trip until the next day
 - Can be ramped up now to 300 V
- Also too high grid current
 - Starting at 600 nA @ 50 V
 - Decreasing to about 100 nA at 200 V
- But falling down very rapidly after increasing the gas flow (2 => 16.7 ml/min)
 - => probably moisture effect on the Araldite





Test QUAD 2 cntd

- At 300 V still no induced current visible with ⁹⁰Sr source
 - **Too high** O_2 level?
- Both too high O₂ level and high moisture level possibly caused by silicon rubber cooling tubes
 - => replaced by Delrin tubing
 - Risky: much more rigid



- Flex broke while replacing the cooling tubing
- Attempt to repair (conductive glue + wire bonding)
- Good result far from guaranteed
- Reinstalled in test box
 - Guard cage sparking at 300 V??
 - Waiting for DAQ test



Starting assembly QUAD 3

- $\sqrt{}$ Wirebond PCB machined on size
- $\sqrt{}$ Stump, coca, wirebond PCB + flex glued together
- $\sqrt{}$ Glue traces at coca removed
- $\sqrt{}$ Guard nuts glued
- \checkmark Chips assembled
- $\sqrt{}$ Wire bonded
- **DAQ** to be tested
 - Bas is busy with it
 - Possible problems DAQ software (I_{bias} of one chip cannot be set)
- HV to grid connections made
 - 4 days needed (3 glue steps)
- HV/connectivity test in air (200 V)
- Installation in test box
- Still to be done
 - DAQ test at the laser setup
 - Configured SPIDR board from Bas available





Wafers

Two low yield wafers (W23 and W30 finally shipped from CERN to Nikhef

- Some 40 days delay
- Received by Yevgen
- Starting photolithography in January
- 2 high yield wafer on hold at Nikhef





Summary

Presently QUAD development is on hold due to the lack of electrical performance testing